



## Product/Process Change Notice - PCN 12\_0253 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Material Report). Any issues with this PCN or requirements to qualify the change (additional data or samples) must be sent to ADI within 30 days of publication date. ADI contact information is listed below.

**PCN Title:** AD8202 Minor Die Revision and Datasheet Change  
**Publication Date:** 05-Nov-2012  
**Effectivity Date:** 03-Feb-2013 *(the earliest date that a customer could expect to receive changed material)*

### Revision Description:

Initial Release

### Description Of Change

1. Increasing polyimide overcoat thickness from 7um to 19um for the wafer fabrication process of the AD8202.
2. Reallocate the use of existing pads on Met1 for use as Kelvin pads which will be connected to the input pins (pins 1 and 8).
3. Remove Min/Max limits rated at 25C (system gain, common mode & voltage offset) from specification table on page 3 and replace with Min/Max limits over the entire temperature range.

### Reason For Change

1. Additional polyimide thickness reduces die sensitivity to package stress.
2. Reallocating the use of existing pads on Met1 for use as Kelvin pads will allow the trim process to give increased accuracy of offset voltage, common mode, and gain.
3. Updating the datasheet to specify Min/Max limits over the entire temperature range reflects the current ADI practice for specifying products used by automotive customers.

### Impact of the change (positive or negative) on fit, form, function & reliability

The additional polyimide thickness and kelvin pads applied to the AD8202 will not affect the fit, form or function of the device. The performance of the part will continue to match the specifications in the datasheet. Data sheet changes will have no effect on production flow or test limits.

### Summary of Supporting Information

Qualification has been performed per AEC-Q100, Stress Test Qualification for Integrated Circuits. See attached Qualification Report Summary.

### Supporting Documents

**Attachment 1: Type:** Qualification Report Summary  
ADI\_PCN\_12\_0253\_Rev\_-\_AD8202\_Rev J\_QP 9943\_summary.doc

**For questions on this PCN, send email to the regional contacts below or contact your local ADI sales representative**

**Americas:** PCN\_Americas@analog.com

**Europe:** PCN\_Europe@analog.com

**Japan:** PCN\_Japan@analog.com

**Rest of Asia:** PCN\_ROA@analog.com

**Appendix A - Affected ADI Models****Added Parts On This Revision - Product Family / Model Number (13)**

AD8202 / AD45091	AD8202 / AD45098	AD8202 / AD8202WYRMZ	AD8202 / AD8202WYRMZ-RL	AD8202 / AD8202WYRZ
AD8202 / AD8202WYRZ-RL	AD8202 / AD8202YRMZ	AD8202 / AD8202YRMZ-R7	AD8202 / AD8202YRMZ-RL	AD8202 / AD8202YRZ
AD8202 / AD8202YRZ-R7	AD8202 / AD8202YRZ-RL	AD8202 / ADW66000YRZ		

**Appendix B - Revision History**

<b>Rev</b>	<b>Publish Date</b>	<b>Effectivity Date</b>	<b>Rev Description</b>
Rev. -	05-Nov-2012	03-Feb-2013	Initial Release

Analog Devices, Inc.

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